

MiNaPAD 2024 – Conference overview

Wednesday June 19th

8h15	Welcome to MiNaPAD – Coffee & Soft drink sponsored by ASE		
9h00	O Opening 🚨 Jean-Marc Yannou		
9h10	Keynote ► The Future of Semiconductor Package Manufacturing in Europe: Growing or Vanishing ▲ Steffen Kröhnert, President & Founder of ESPAT Consulting – SEMI Europe Manager, Germany		
	Session A ► AI Applications ♀ Auditorium	Session B ► Attachment materials ♀ Mont Blanc	
9h45	Detection and measurement of solder voids in X-ray of led assembly with YOLO v8 Yasser Almehio, VALEO, France	The Application of Low Temperature Self-Assembly Sn Based Glue Glenn Lin, ASE group, Taiwan	
10h15	Solder paste development using Al A Melanie Mathon, INVENTEC, France	New Bare Copper Compatible Die Attach Developments Improving Reliability and Thermal at Lower Cost Ruud De Wit, HENKEL, The Netherlands	
10h45	Exhibition Opening – Coffee break sponsored by STMicroelectronics		
	Session C ► Interconnections ♀ Auditorium	Session D ► PCB Substrates ♀ Mont Blanc	
11h15	Integration of III-V GaN amplifiers of an antenna in package receiver in PCB- based embedding technology Tekfouy Lim, FRAUNHOFER IZM, Germany	Advanced IC substrates – Challenges in the manufacturing and supply chain Roland Steim, DYCONEX, Switzerland	
11h45	Alternative approach to Die-to-Wafer bonding utilizing atmospheric plasma	High Density Organic Substrates for Chinlet and High Frequency Application	

11h45	Alternative approach to Die-to-Wafer bonding utilizing atmospheric plasma cleaning Laniel Pascual, ONTOS - USA	High Density Organic Substrates for Chiplet and High Frequency Application Lars Bottcher, FRAUNHOFER IZM, Germany
12h15	Clips bonding using re-metallization techniques Wilfrid Aklamavo, SERMA Microelectronics, France	
12h45	Lunch sponsored by Teledyne e2V	♥ Exhibition Hall
	Session E ► Process Optimization 1 ♀ Auditorium	Session F ► Reliability 1 ♀ Mont Blanc
13h45	An innovative deposition technology for conductive & dielectric materials; Multimaterials, Multilayers, Contactless High-Resolution High-Speed Deposition & Stéphane Étienne, I-O-TECH, Israel	Robustness and environmental impact of under bump metallization for wafer level balling Arnaud Garnier, CEA LETI, France
14h15	SWEET (Side Wall ExquisiteEnveloping Technology) to protect WLSCP Shih Chieh Tang, ASE group	SACN doped Mn solder balls oxidation study for BGA's reliability performance Stelliane Grolier Lee, STMicroelectronics, France
14h45	Post plasma dicing clean in Batch spray equipment with sulfuric ozone mixtures A Moritz Mittermayr, SICONNEX, Austria	Experimental study of interfacial adhesion of passivation/resin with shear test: first learnings A Marie Dugor Dentone, STMicroelectronics, France
15h15	5 Exhibition – Coffee break sponsored by Accelonix	
	Session G ► Dicing/Picking ♀ Auditorium	Session H ► Flip Chip Process ♀ Mont Blanc
15h45	Plasma Singulation of Single Power Diodes Bonded by Intermetallic Eutectic Technique Sabrina Roza-Ortiz, PLASMATHERM, USA	Development of a dipping process for silver sintered flip chip interconnexion Let Céline Feautrier, CEA LETI, France
16h15	Latest approaches of dicing and grinding for semiconductor device manufacturing & Benjamin Bernard, DISCO, Germany	Flux less soldering in activated hydrogen atmosphere L Jeff Blair, SIKAMA, USA
16h45	Industrial Approach for Plasma Dicing: Advances and Challenges Lucile Broussous, STMicroelectronics, France	Displacement mechanisms of polymer adhesives used in the flip chip interconnected structures Nacer Aitmani, CEA LETI, France

17h15	Leslie Lea, PLASMATHERM, USA	Innovative interconnect material for semiconductor assembly and advanced packaging Sze Pei Lim, INDIUM, United Kingdom
17h45	Exhibition	♥ Exhibition Hall
18h30	Social Event: Departure	

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8h30	Opening exhibition and conferences		
9h10	Keynote ► What are our common Challenges for Future? Thomas Romont, Senior PCB Expert, IFTEC, France		
	Session J ► Power Management ♀ Auditorium	Session K ► Characterization ♀ Mont Blanc	
9h45	Understanding Criticality of Thermal Performance in Thermal Interface Material for Automotive Applications	Dual blocks QFN warpage characterization Leone, STMicroelectronics, Italy	
10h15	Packaging and reliability challenges for Innovative Automative Grade current sensors Lastair Attard, UTAC, Switzerland	Die bending methodology to explore Deep Trench Isolation crack initiation risk in Backside Imager Sensors & Caroline Moutin, STMicroelectronics, France	
10h45	♥ Exhibition – Coffee break sponsored by Capling		
	Session L ► Process Optimization 2 ♀ Auditorium	Session M ► Sustainability ♀ Mont Blanc	
11h15	In Situ characterization of plasma species for process optimization and improvement Djamila Chou, STMicroelectronics, France	Fabrication of low density3D PCB using piezo-ink jet and 6 axis robots Davide Benneventi, INPG, France	
11h45	Direct silicon wafer bonding outside cleanroom conditions L Chrysoula Nikoleta Manolaki, DTU Electro, Denmark	High Precision Capillary Printing HPCAP and its sustainable value in electronics Lulien Vitiello, HUMMINK, France	
12h15	Two steps collective bonding, from dicing-tape to device over 10000 UPH Aurélien Griffart, SET, France	Sustainable and circular PCB using biobased/biodegradable substrates and metals bioleaching & Vincent Grennerat, INPG CROMA, France	
12h45	♥ Exhibition – Lunch sponsored by Kyocera		
	Session N ► Molding process ♀ Auditorium	Session O ► Reliability 2 ♀ Mont Blanc	
13h45	Environment-friendly Epoxy Molding Compounds for Semiconductors and Automotive	Enhanced Board Level Reliability Method for High Performance Automotive BGA Packages & Nohora Caicedo, STMicroelectronics, France	
14h15	Advanced Mold Design Solutions to Counteract Surface Discoloration in Flip Chip Encapsulation & Roberto Dossi, ASE group, Taiwan	The Effects of Voids on Solder Joint Reliability in First Level Interconnect Sze Pei Lim, INDIUM, United Kingdom	
	Session P ► Interposer 2.5D TSV 3D ♀ Auditorium		
14h55	Design and verification of a 2.5 Heterogeneous Integration Platform Jeroen Schelkens & Dimitrios Tsiakos, IMEC, Belgium		
15h25	Unlocking the Trends and Challenges in Advanced 3D Heterogeneous Integration Manufacturing A Rayane Mazari, YOLE Group, France		
	Hermetically sealed glass interposer platform for photonics integrated circuits L Kevin Kroehnert, FRAUNHOFER IZM, Germany		
15h50			